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| <b>Search Notes</b><br><br> | <b>Application/Control No.</b><br><br>10551039 | <b>Applicant(s)/Patent Under Reexamination</b><br><br>FUJITA ET AL. |
|  | <b>Examiner</b><br><br>NIKHIL SRIRAMAN         | <b>Art Unit</b><br><br>3664   |

| SEARCHED |                         |            |          |
|----------|-------------------------|------------|----------|
| Class    | Subclass                | Date       | Examiner |
| 700      | 245, 248, 249, 250, 253 | 12/20/2008 | NS       |

| SEARCH NOTES   |            |          |
|--|------------|----------|
| Search Notes   | Date       | Examiner |
| Consulted with Marc McDieunel  | 12/20/2008 |          |
| Assignee search on East, Inventor search on eDan   |            |          |
| NPL, including IEEE databases searched (see attached history)  |            |          |
| Reviewed submitted IDS references  | 7/12/2009  |          |
| Updated search in light of claim amendments; consulted with Examiner Jorge Peche and Examiner Kyung Kim on search strategy on claim interpretation | 12/19/2009 |          |

| INTERFERENCE SEARCH |          |      |          |
|---------------------|----------|------|----------|
| Class               | Subclass | Date | Examiner |
|                     |          |      |          |

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